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XLAUI/CAUI Jitter Tolerance Test Proposal

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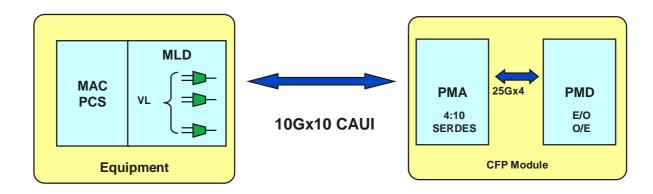
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1

Introduction

- * There are two Editor's Note on 83A 5.2.2.
- * Those are interference tolerance test and jitter tolerance test pattern. This proposal resolves these two unclear items.



83A.5.2.2 Jitter tolerance

[Editor's note: (to be removed prior to publication) - An interference tolerance test is required]

[Editor's note: (to be removed prior to publication) -In addition to PRBS31, consider including appropriate patterns when performing jitter measurements e.g., MLD and other representative patterns.]



Interference tolerance test system proposal

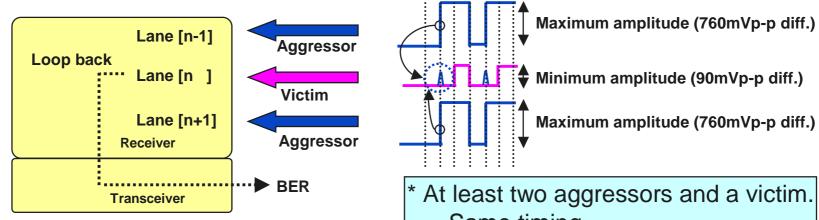


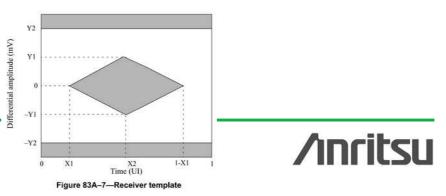
Table 83A–1—Transmitter characteristics

Parameter	Value	Units
Signalling speed per lane (range)	$10.3125\pm100\text{ ppm}$	GBd
Single-ended output voltage range		
maximum	4.0	V
minimum	-0.4	V
Maximum Differential Output Voltage, peak-to-peak	760	mV

Table 83A–2—Receiver characteristics

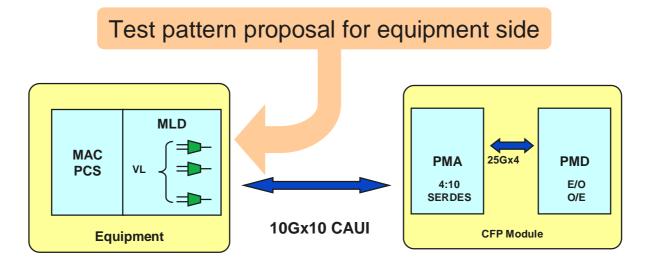
Parameter	Value	Units
Signalling speed per lane (range)	10.3125 ± 100 ppm	GBd
Minimum Differential Input Voltage, p-p	See receiver eye mask definition	mV
Receiver eye mask definition Y1 ^d	45	mV

- Same timing
- Aggressors
 - Maximum amplitude
 - Same pattern PRBS 23
- * A victim
 - Minimum amplitude
 - PRBS 31



Jitter Tolerance Test Pattern Proposal

- * PRBS31 is good enough for testing jitter tolerance of optical module side. It is just simple physical characteristics test.
- * For equipment side, test pattern should be included "Alignment Marker" to drive alignment circuit.

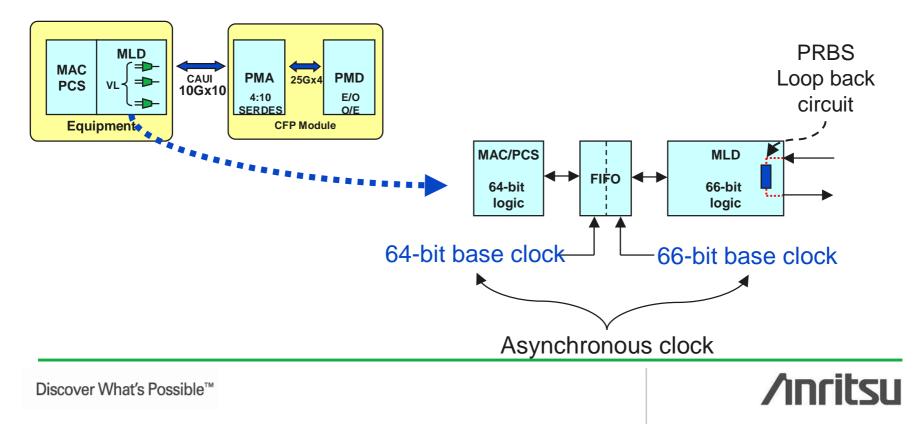




Equipment Circuit Assumption

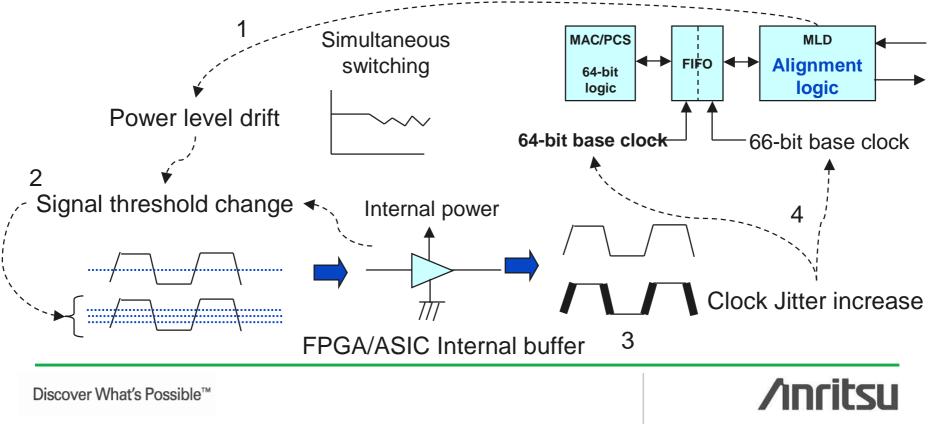
* Equipment circuit assumptions

- Skew alignment must be huge logic circuit.
- During PRBS loop back circuit works, alignment circuit does not work.
- PRBS Loop back circuit is smaller than skew alignment circuit.
- The circuit uses at least two asynchronous clocks (64-bit and 66-bit logic).



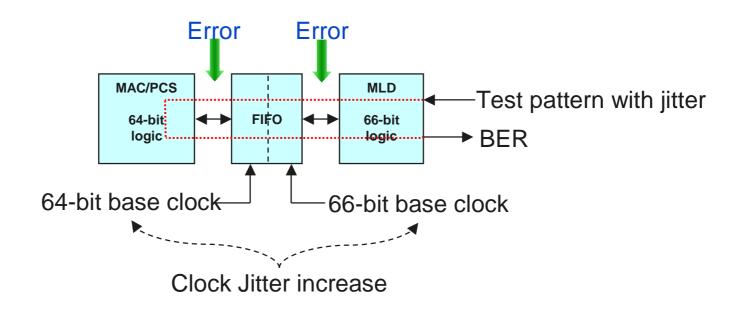
Increasing jitter inside of large scale logic circuit -1

- -1. Simultaneous switching of large-scale circuit in FPGA/ASIC causes internal power level drift.
- -2. Power level drift changes internal buffer threshold level.
- -3. Jitter on buffer output signal increases.
- -4. The amount of jitter is different between asynchronous clocks (64-base, 66-base)



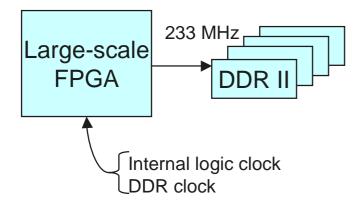
Increasing jitter inside of large scale logic circuit -2

- The different amount of jitter decrease in phase margin at FIFO. Or it may cause error at FIFO in the worst case.
- To test jitter tolerance under the worst condition, skew alignment circuit should work.
 ➔ So test pattern should be included "Alignment marker" to drive alignment circuit.

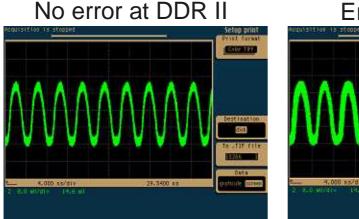


Increasing jitter inside of large scale logic circuit -3

-- Example --



Simultaneous switching causes internal power level drift between two asynchronous clocks in FPGA causing error at DDR access



Error at DDR II



Jitter Tolerance Test Pattern Proposal

For equipment side, jitter tolerance test pattern should be included "Alignment Marker" to make the worst condition.

